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ICS 31.200
CCS L55

SJ

INDUSTRY STANDARD OF THE

PEOPLE'S REPUBLIC OF CHINA

SJ 21473.2-2018

Military integrated circuit electromagnetic immunity measurement method. Part 2: Radiation immunity measurement-TEM cell and broadband TEM cell method

军用集成电路电磁抗扰度测量方法 第2部分 辐射抗扰度测量- TEM小室和宽带TEM小室法

(English Translation)

Implemented on: March 1, 2019

Issued by: Ministry of Industry and Information Technology

Preview: page 1 of 3 shown, 16 in the full document. Complete English PDF, instant download:
https://chinastandards.org/standards/sj-21473-2-2018

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Table of Contents

[Preview only]
1 Scope
2 Normative References
2.1 Terms
3 Terms and Definitions
4 Overview
4.1 General requirements
5 Technical Requirements
6 Calibration conditions
6.1 Environmental conditions
6.2 Measurement standards and other equipment
7 Calibration items and calibration methods
7.1 Calibration Items
7.2 Calibration method
8 Expression of calibration results
9 Recalibration interval

1 Foreword

SJ 21473.2-2018 is issued by Ministry of Industry and Information Technology.

It is one of 3 parts of the SJ 21473 series.

The SJ prefix, without a suffix, marks a mandatory standard: within its scope, compliance is required.

2 Scope Preview

SJ 21473.2-2018 falls under ICS 31.200, in the field of electronics.

This catalogue holds 133 other SJ standards in that field.

In this catalogue, SJ standards carry edition years from 1965 to 2021.

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3 About this standard

Sector: Electronics Industry Standard

Issued by: Ministry of Industry and Information Technology

English translation: about 16 pages (approximate)

Chinese original: about 24,233 characters

4 Related standards

Other parts of this standard:

SJ 21473.6-2021 - Methods of measuring electromagnetic immunity of military integrated circuits - Part 6: Impulse immunity measurement - Synchronous transient injection method

SJ 21473.7-2021 - Methods of measuring electromagnetic immunity of military integrated circuits - Part 7: Measurement of pulse immunity - non-synchronous transient injection method

Standards on related subjects:

GB/T 46280.2-2025 - Specification for chiplet interconnection interface - Part 2: Protocol layer technical requirements

SJ/T 11891-2023 - Energy efficiency measurement method for LED displays

GB/T 35010.6-2018 - Semiconductor die products -- Part 6: Requirements for concerning thermal simulation

5 Classification and status

International classification (ICS): 31.200

Chinese Standard Classification (CCS): L 55

Prefix SJ: mandatory standard.

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